


<b>Search Notes</b>  	<b>Application/Control No.</b>  10550577	<b>Applicant(s)/Patent Under Reexamination</b>  HAYASHI ET AL.
	<b>Examiner</b>  /Susan W Berman/	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
		7-15-08	sb
430	287.1	7-15-08	sb
430	321	7-15-08	sb
522	121	7-15-08	sb
522	10	7-15-08	sb
522	14	7-15-08	sb
522	39	7-15-08	sb
522	65	7-15-08	sb

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (see printout)	7-16-08	sb
JAP machine translation of cited JP docs	7-16-08	sb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner